

MS12BS200S

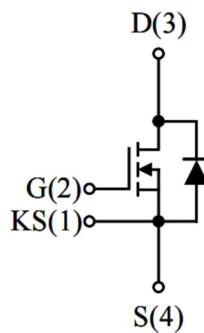
Single-Bridge Module with parallel SiC MOSFETs

Technical Features:

- Ultra-Low Loss
- Zero Reverse Recovery
- Low Thermal Resistance
- Standard SOT227 Package
- High Frequency Operation
- High Performance AMB Ceramic

V_{DS}	1200V
I_D(T_C=100°C)	160A
R_{DS(on)}	6.50mΩ

Package 38mm × 25mm × 12mm



Part Number	Package	Marking
MS12BS200S	Single Bridge OM1 Module	MS12BS200S

Maximum Ratings (T_C=25°C unless otherwise specified)

Symbol	Parameter	Value	Unit	Test Conditions	Notes
V _{DSmax}	Drain-Source Voltage	1.2	kV		
V _{GSmax}	Gate-Source Voltage	-10/+22	V	Absolute Maximum Values	Fig.28
V _{GSoP}	Gate-Source Voltage	-4/+18	V	Recommended Operational Values	
I _D	Continuous Drain Current	230	A	V _{GS} =18V, T _C =25°C, T _J ≤175°C	
		140		V _{GS} =18V, T _C =100°C, T _J ≤150°C	
		160		V _{GS} =18V, T _C =100°C, T _J ≤175°C	
I _{SD(BD)}	DC Source-Drain Current (Body Diode)	108	A	V _{GS} =-4V, T _C =100°C, T _J ≤175°C	
I _{D(pulse)}	Pulsed Drain Current	320	A	Pulse Width t _p Limited by T _{Jmax}	
P _D	Power Dissipation	710	W	T _C =25°C, T _J ≤175°C	
T _{Jmax}	Maximum Junction Temperature	175	°C		
T _{J,opt}	Recommended operating junction temperature	-40 to +150	°C		
T _{C, T_{STG}}	Case & Storage Temperature Range	-40 to +125	°C		
V _{isol}	Case Isolation Voltage	4.0	kV	AC, 50 Hz, 1min	

Electrical Characteristics ($T_C=25^\circ\text{C}$ unless otherwise specified)

Symbol	Parameter	Min.	Typ.	Max.	Unit	Test Conditions	Notes
V_{DSS}	Drain Source Blocking Voltage	1.2			kV	$V_{GS}=0\text{V}$, $I_D=200\mu\text{A}$	
$V_{GS(\text{th})}$	Gate Threshold Voltage	1.8	2.9	3.8	V	$V_{DS}=V_{GS}$, $I_D=54\text{mA}$	
I_{DSS}	Zero Gate Voltage Drain Current		2	100	μA	$V_{DS}=1.2\text{kV}$, $V_{GS}=0\text{V}$	
I_{GSS}	Gate-Source Leakage Current		2	400	nA	$V_{GS}=18\text{V}/-4\text{V}$, $V_{DS}=0\text{V}$	
$R_{DS(\text{on})}$	On State Resistance		6.50	8.50	$\text{m}\Omega$	$V_{GS}=18\text{V}$, $I_{DS}=160\text{A}$, $T_J=25^\circ\text{C}$	Fig.5 Fig.6,7
			10.50			$V_{GS}=18\text{V}$, $I_{DS}=160\text{A}$, $T_J=125^\circ\text{C}$	
			12.00			$V_{GS}=18\text{V}$, $I_{DS}=160\text{A}$, $T_J=150^\circ\text{C}$	
			13.50			$V_{GS}=18\text{V}$, $I_{DS}=160\text{A}$, $T_J=175^\circ\text{C}$	
g_{fs}	Transconductance		150		S	$V_{DS}=20\text{V}$, $I_{DS}=300\text{A}$	Fig.8
			160			$V_{DS}=20\text{V}$, $I_{DS}=300\text{A}$, $T_J=150^\circ\text{C}$	
Q_{GS}	Gate-Source Charge		120		nC	$V_{DD}=800\text{V}$, $V_{GS}=-4\text{V}/+18\text{V}$, $I_D=200\text{A}$, Per JEDEC 24 pg 27	
Q_{GD}	Gate-Drain Charge		256				
Q_G	Total Gate Charge		492				
C_{iss}	Input Capacitance		10.4n		F	$V_{GS}=0\text{V}$, $V_{DS}=1000\text{V}$, $f=100\text{kHz}$, $V_{AC}=25\text{mV}$	Fig.14
C_{oss}	Output Capacitance		450p				
C_{rss}	Reverse Transfer Capacitance		38p				
$R_{G(\text{int})}$	Internal Gate Resistance		3.6		Ω	$V_{GS}=0\text{V}$, $f=100\text{kHz}$, $V_{AC}=25\text{mV}$	
E_{on}	Turn-On Energy				mJ		Fig.16 -
	$T_J=25^\circ\text{C}$		3.72				
	$T_J=125^\circ\text{C}$		3.77				
	$T_J=150^\circ\text{C}$		3.88				
E_{off}	$T_J=175^\circ\text{C}$		3.98				
	Turn-Off Energy				mJ		Fig.20
	$T_J=25^\circ\text{C}$		1.95				
	$T_J=125^\circ\text{C}$		1.95				
$t_{d(on)}$	$T_J=150^\circ\text{C}$		1.96			$V_{DD}=600\text{V}$, $V_{GS}=-4\text{V}/+18\text{V}$ $I_D=200\text{A}$, $R_{G(\text{off})}=1\Omega$, $R_{G(\text{on})}=4.7\Omega$ Load=30 μH	
	$T_J=175^\circ\text{C}$		1.97				
	Turn-on delay time						
	$T_J=25^\circ\text{C}$		56				
t_r	$T_J=125^\circ\text{C}$		49		ns		
	$T_J=150^\circ\text{C}$		48				
	$T_J=175^\circ\text{C}$		48				
	Rise Time						
$t_{d(off)}$	$T_J=25^\circ\text{C}$		30				
	$T_J=125^\circ\text{C}$		27				
	$T_J=150^\circ\text{C}$		27				
	$T_J=175^\circ\text{C}$		26				
$t_{d(off)}$	Turn-off delay time						
	$T_J=25^\circ\text{C}$		84				
	$T_J=125^\circ\text{C}$		86				
	$T_J=150^\circ\text{C}$		89				
	$T_J=175^\circ\text{C}$		90				

Electrical Characteristics ($T_C=25^\circ\text{C}$ unless otherwise specified)

Symbol	Parameter	Min.	Typ.	Max.	Unit	Test Conditions	Notes
t_f	Fall Time $T_J=25^\circ\text{C}$ $T_J=125^\circ\text{C}$ $T_J=150^\circ\text{C}$ $T_J=175^\circ\text{C}$		26 26 26 27		ns	$V_{DD}=600\text{V}$, $V_{GS}=-4\text{V}/+18\text{V}$ $I_D=200\text{A}$, $R_{G(\text{off})}=1\Omega$, $R_{G(\text{on})}=4.7\Omega$ Load=30μH	

Thermal Characteristics

Symbol	Parameter	Min.	Typ.	Max.	Unit	Test Conditions	Notes
$R_{thJC\text{ MOS}}$	Junction-to-Case Thermal Resistance for MOSFET	-		0.21	K/W	Per SiC MOSFET	Fig.23
$R_{thJC\text{ BD}}$	Junction-to-Case Thermal Resistance for Body Diode	-		0.22	K/W	Per Body Diode	

Diode Characteristics ($T_J = 25^\circ\text{C}$ unless otherwise specified)

Symbol	Parameter	Min.	Typ.	Max.	Unit	Test Conditions	Notes
V_{SD}	Diode Forward Voltage		4.61		V	$I_F=160\text{A}$, $T_J=25^\circ\text{C}$, $V_{GS}=-4\text{V}$	Fig.11
			4.20			$I_F=160\text{A}$, $T_J=125^\circ\text{C}$, $V_{GS}=-4\text{V}$	
			4.13			$I_F=160\text{A}$, $T_J=150^\circ\text{C}$, $V_{GS}=-4\text{V}$	
			4.07			$I_F=160\text{A}$, $T_J=175^\circ\text{C}$, $V_{GS}=-4\text{V}$	
t_{rr}	Reverse Recovery Time $T_J=25^\circ\text{C}$ $T_J=125^\circ\text{C}$ $T_J=150^\circ\text{C}$ $T_J=175^\circ\text{C}$		25 34 35 36		ns		
Q_{RR}	Reverse Recovery Charge $T_J=25^\circ\text{C}$ $T_J=125^\circ\text{C}$ $T_J=150^\circ\text{C}$ $T_J=175^\circ\text{C}$		1.04 2.76 3.27 3.69		μC	$V_{DD}=600\text{V}$, $V_{GS}=-4\text{V}/+18\text{V}$ $I_D=200\text{A}$, $R_{G(\text{off})}=1\Omega$, $R_{G(\text{on})}=4.7\Omega$ Load=30μH	
I_{RRM}	Peak Reverse Recovery Current $T_J=25^\circ\text{C}$ $T_J=125^\circ\text{C}$ $T_J=150^\circ\text{C}$ $T_J=175^\circ\text{C}$		67 133 148 162		A		
E_{RR}	Reverse Recovery Energy $T_J=25^\circ\text{C}$ $T_J=125^\circ\text{C}$ $T_J=150^\circ\text{C}$ $T_J=175^\circ\text{C}$		0.34 0.73 0.83 0.91		mJ	$V_{DD}=600\text{V}$, $V_{GS}=-4\text{V}/+18\text{V}$ $I_D=200\text{A}$, $R_{G(\text{off})}=1\Omega$, $R_{G(\text{on})}=4.7\Omega$ Load=30μH	Fig.21 Fig.22

Module Physical Characteristics

Symbol	Parameter	Typ.	Unit	Test Conditions	Notes
	Material of Module Baseplate	Cu			
V_{isol}	Isolation Test Voltage	2.5	kV	RMS, f=50Hz, t=1min	
T_{stg}	Storage Temperature	-55 to 150	°C		
da	Clearance	4.4	mm	Terminal to Terminal	
		6.8	mm	Terminal to Heatsink	
ds	Creepage	10.5	mm	Terminal to Terminal	
		8.5	mm	Terminal to Heatsink	
M_s	Mounting Torque of Screws	0.9~1.5	N · m	Baseplate To Heatsink, Screw M6	
M_T	Mounting Torque of Screws	0.9~1.3	N · m	To Terminals, Screw (M4*9mm)	
G	Weight	29	g		
CTI	Comparative Tracking Index	>200			

Typical Performance

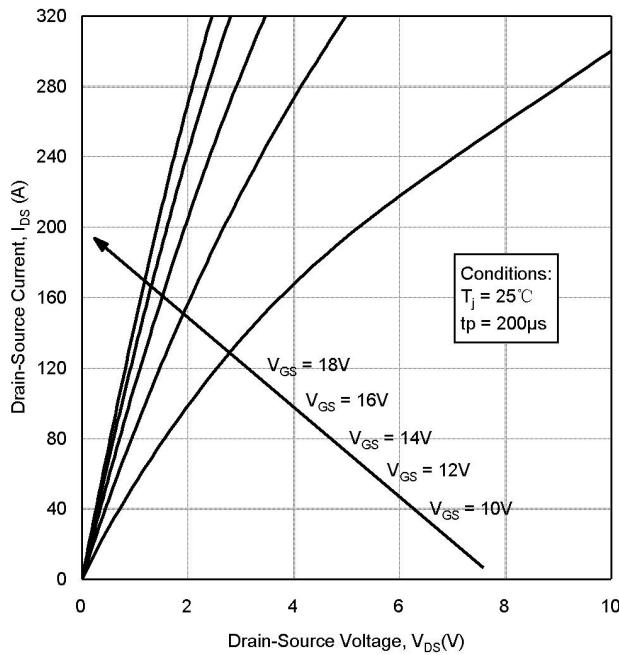


Figure 1. Output Characteristics $T_j=25^\circ\text{C}$

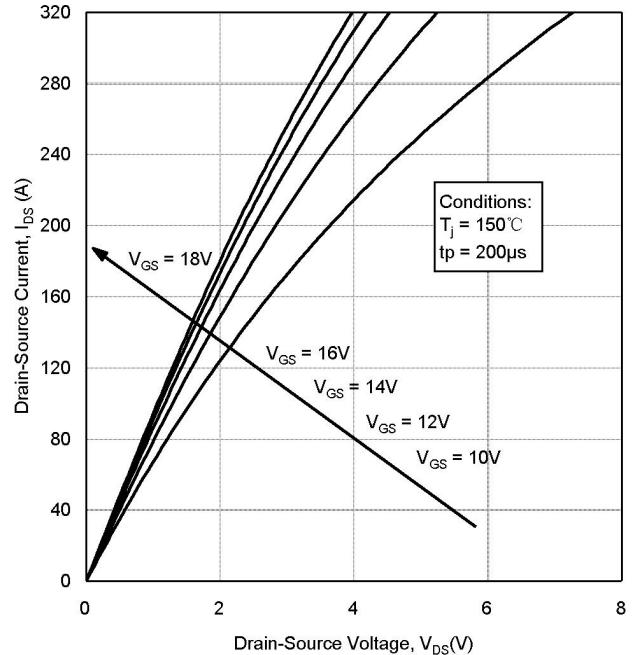


Figure 2. Output Characteristics $T_j=150^\circ\text{C}$

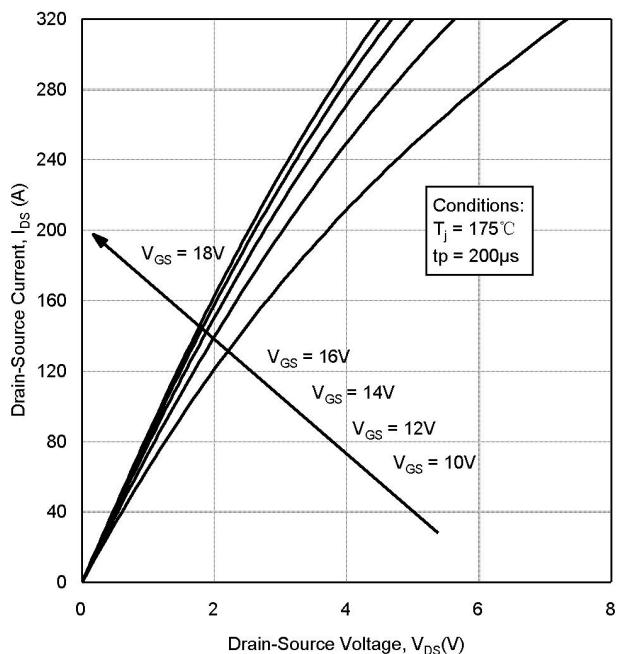


Figure 3. Output Characteristics $T_j=175^\circ\text{C}$

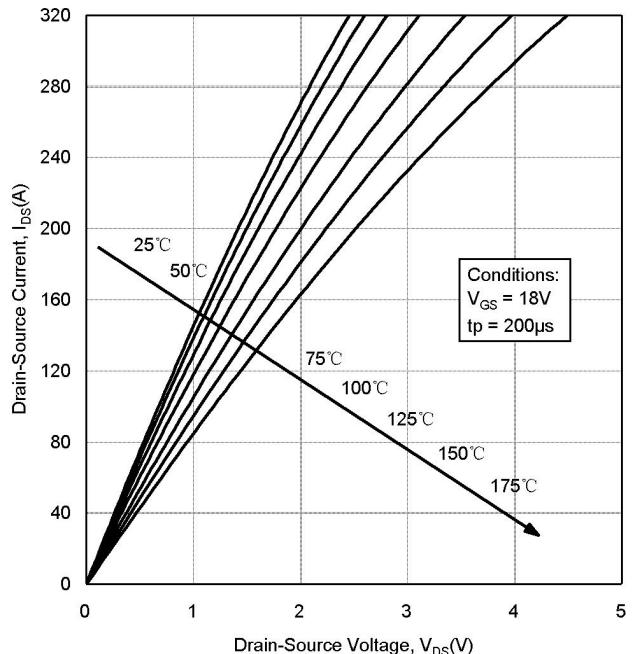


Figure 4. Output Characteristics vs. Temperature

Typical Performance

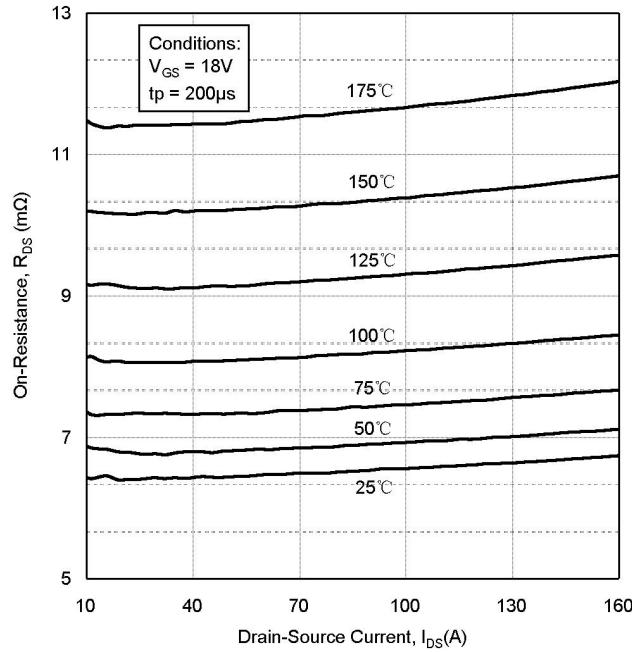


Figure 5. On-Resistance vs. Drain Current

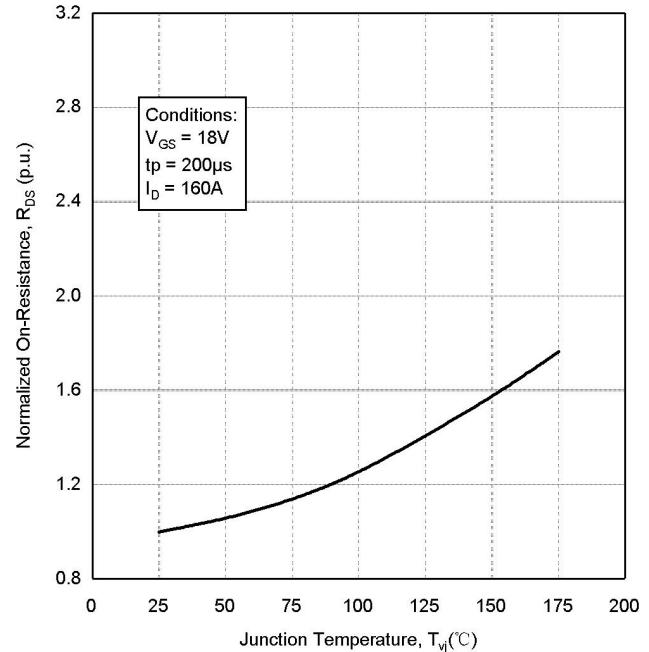


Figure 6. Normalized On-Resistance vs. Junction Temperature

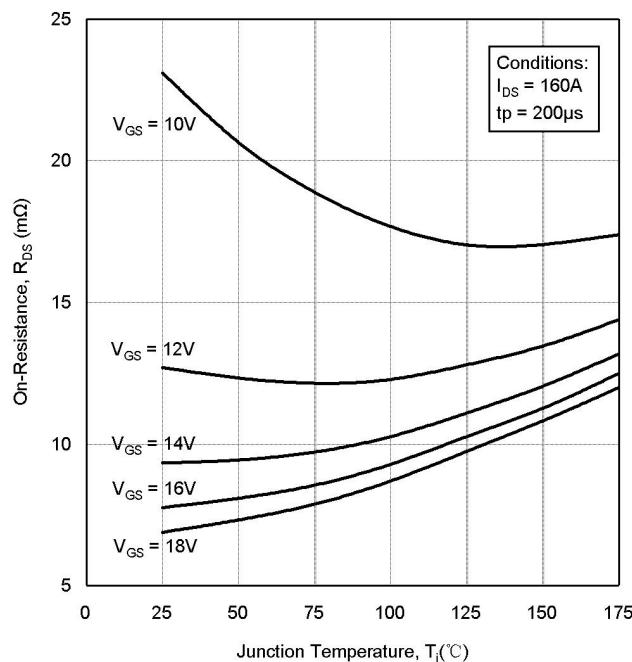


Figure 7. On-State Resistance vs. Junction Temperature

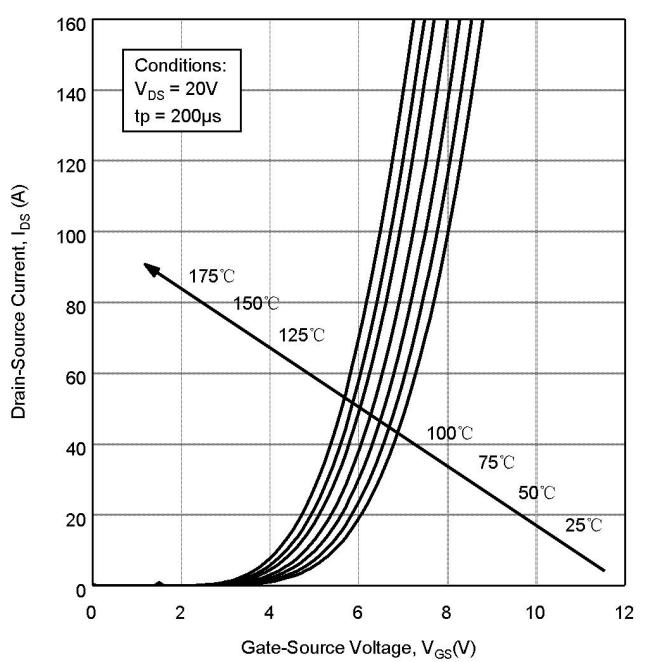


Figure 8. Transfer Characteristics

Typical Performance

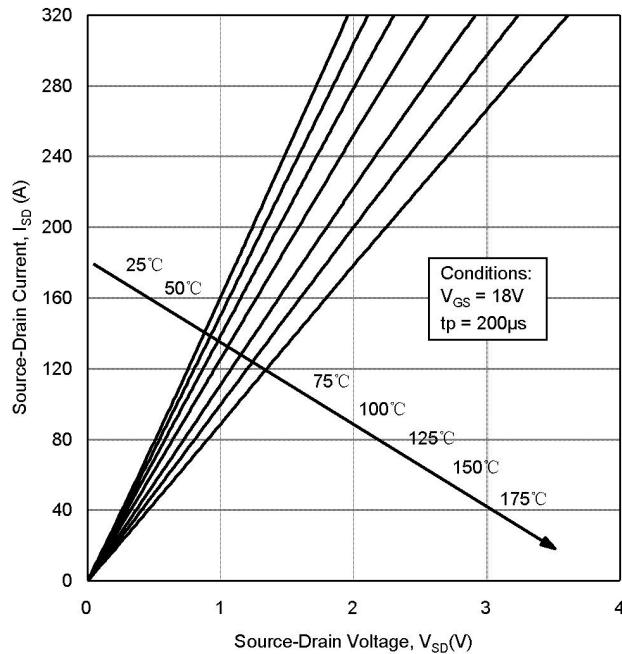


Figure 9. Diode Characteristics

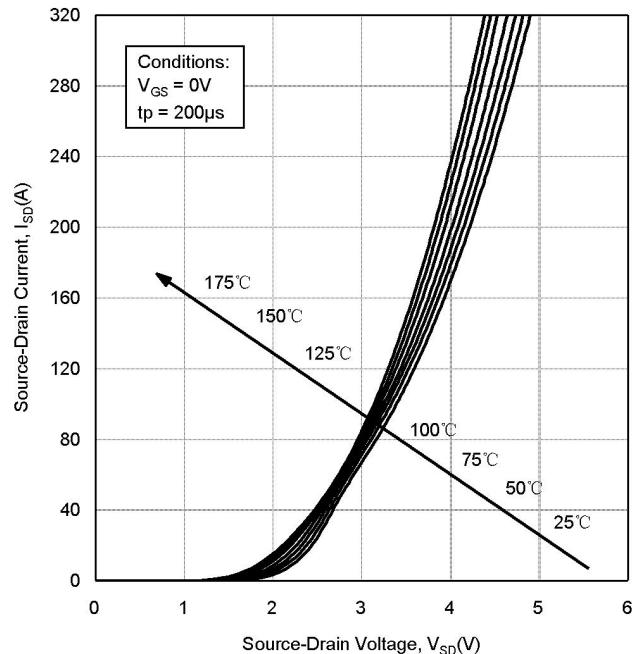


Figure 10. 3rd Quadrant Characteristic vs. Junction Temperature at $V_{GS}=0V$

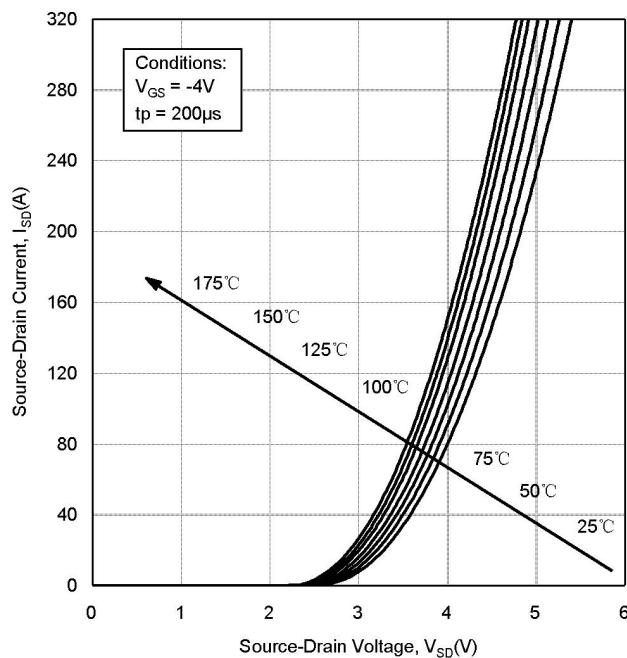


Figure 11. 3rd Quadrant Characteristic vs. Junction Temperature at $V_{GS}=-4V$ (Body Diode)

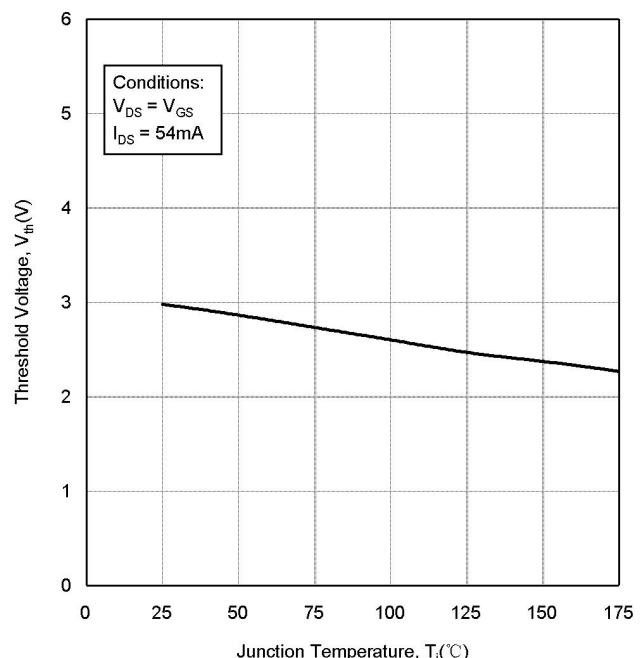


Figure 12. Threshold Voltage vs. Junction Temperature

Typical Performance

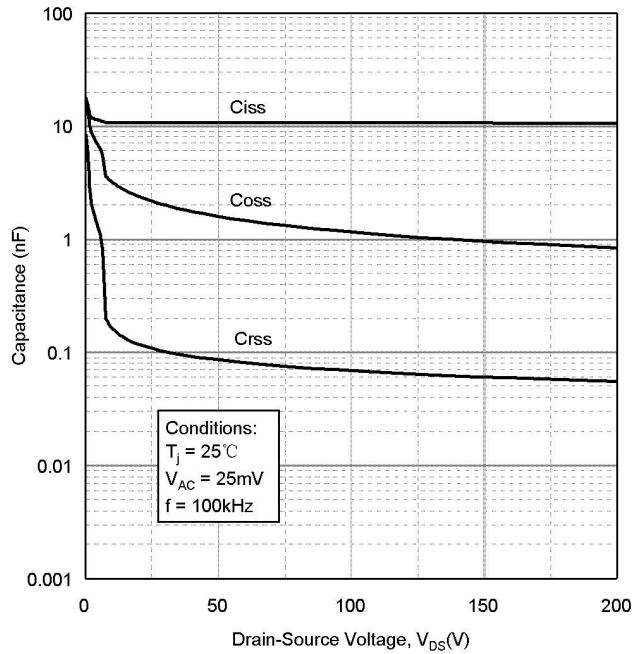


Figure 13. Capacitances vs. Drain-Source (0-200V)

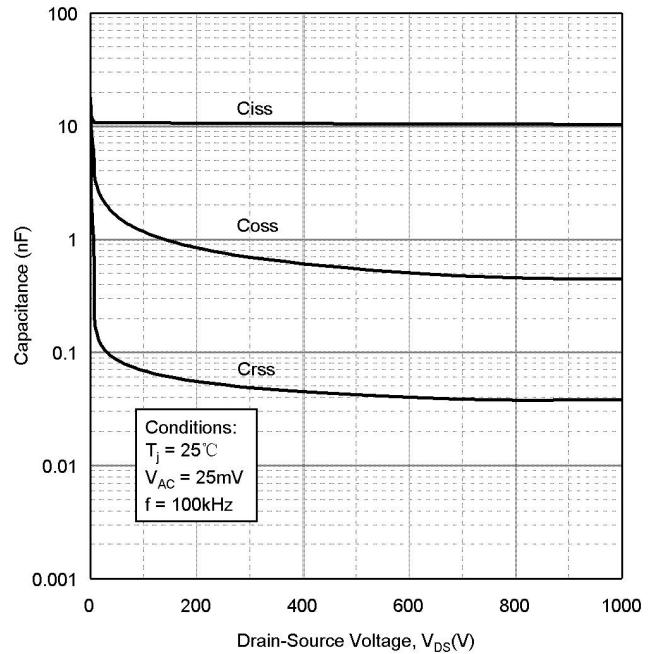


Figure 14. Capacitances vs. Drain-Source (0-1000V)

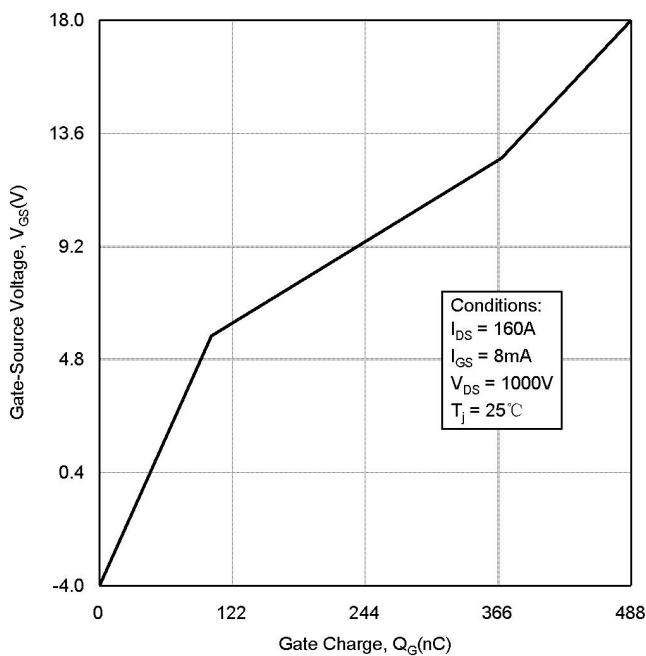


Figure 15. Gate Charge Characteristics

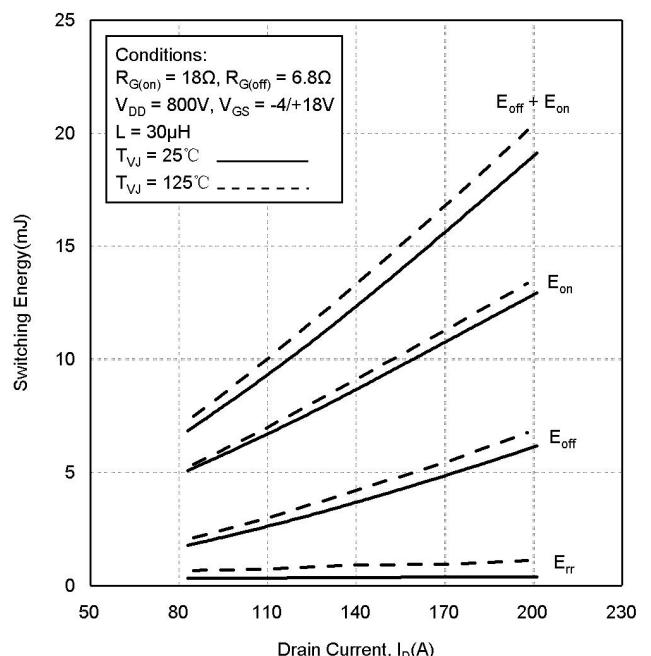


Figure 16. Inductive Switching Energy vs. Drain Current ($T_j=25^\circ\text{C}$, $T_j=125^\circ\text{C}$)

Typical Performance

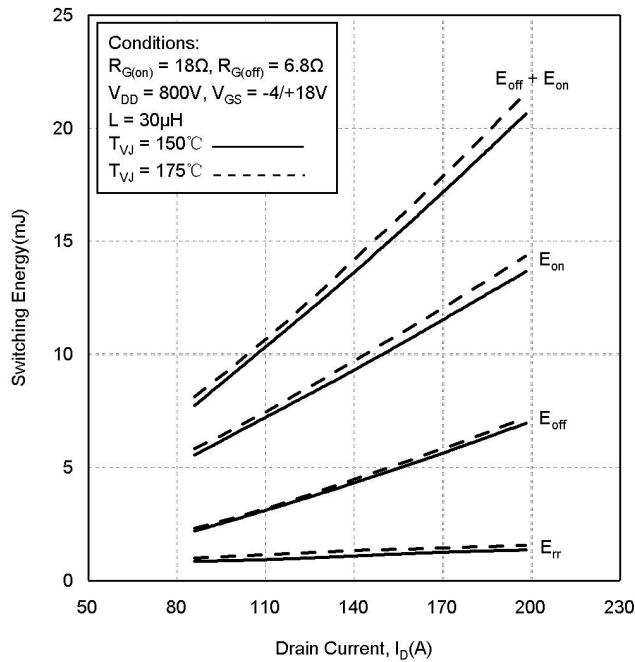


Figure 17. Inductive Switching Energy vs. Drain Current ($T_j=150^\circ C$, $T_j=175^\circ C$)

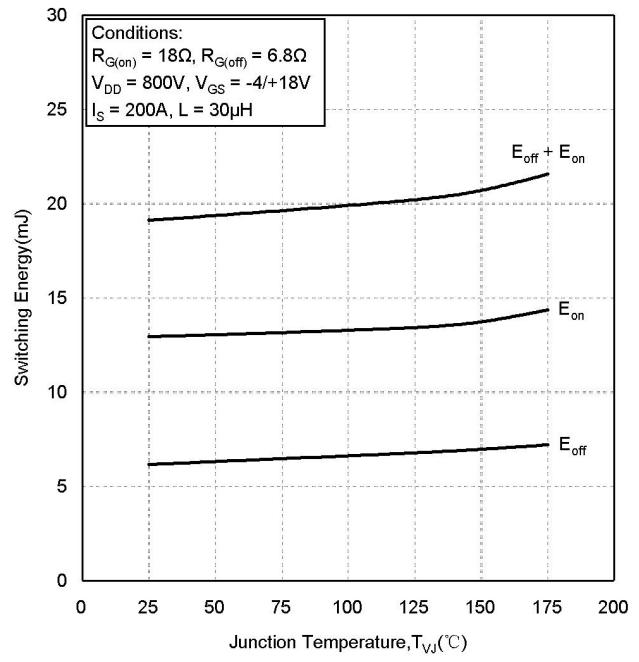


Figure 18. MOSFET Switching Energy vs. Junction Temperature

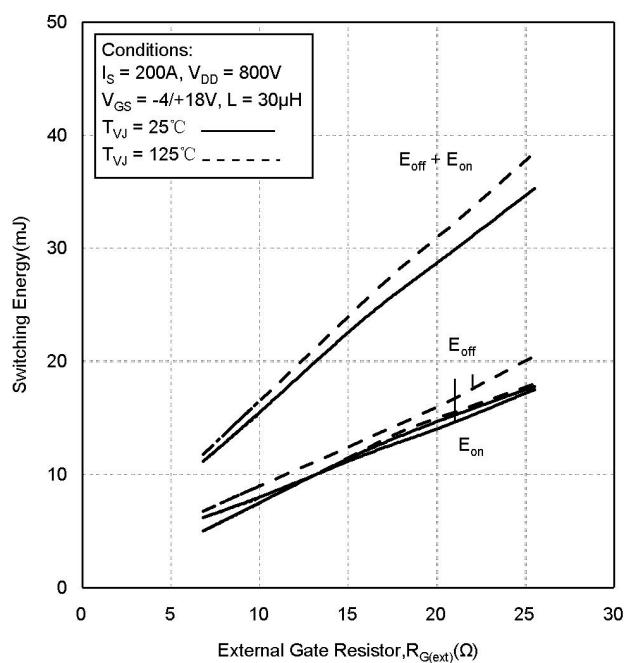


Figure 19. Inductive Switching Energy vs. $R_{G(ext)}$ ($T_j=25^\circ C$, $T_j=125^\circ C$)

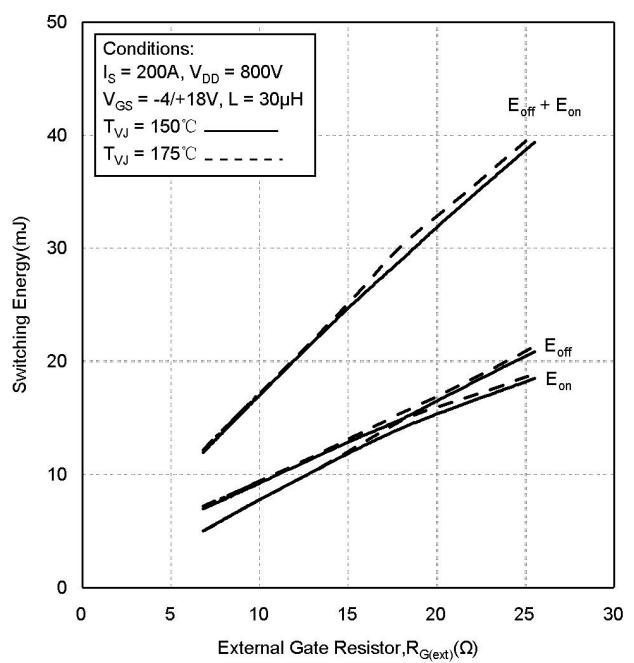


Figure 20. Inductive Switching Energy vs. $R_{G(ext)}$ ($T_j=150^\circ C$, $T_j=175^\circ C$)

Typical Performance

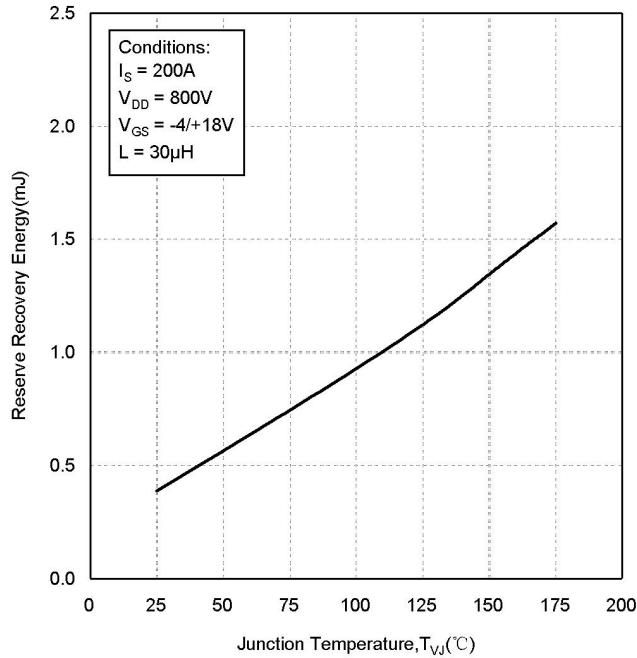


Figure 21. Reverse Recovery Energy vs. Junction Temperature

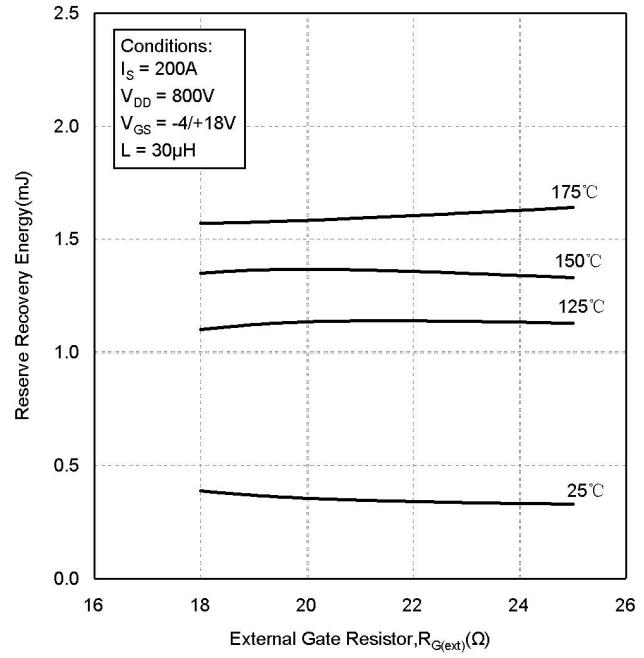


Figure 22. Reverse Recovery Energy vs. External Gate Resistance

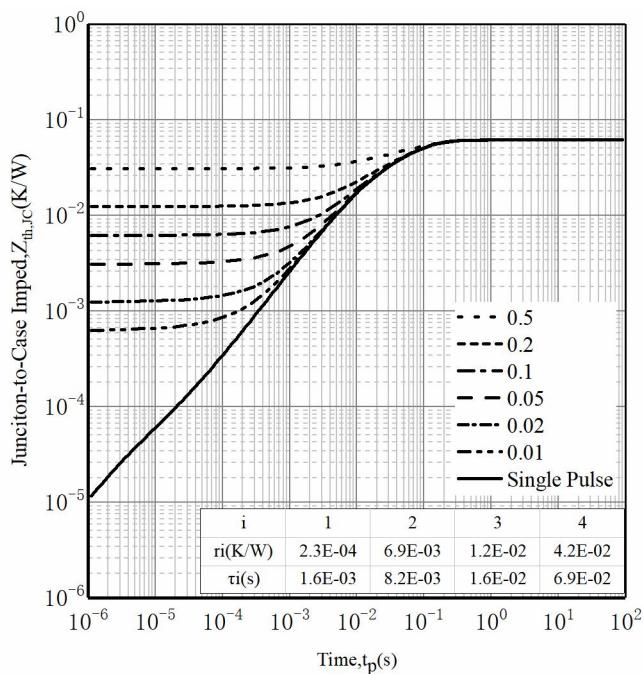


Figure 23. MOSFET Junction to Case Transient Thermal Impedance, $Z_{th,JC}$ (K/W)

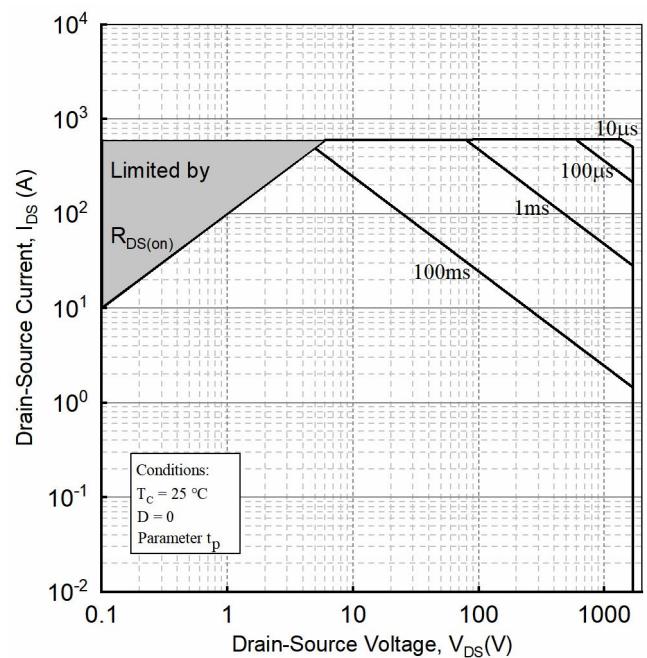


Figure 24. Forward Bias Safe Operating Area (FBSOA)

Typical Performance

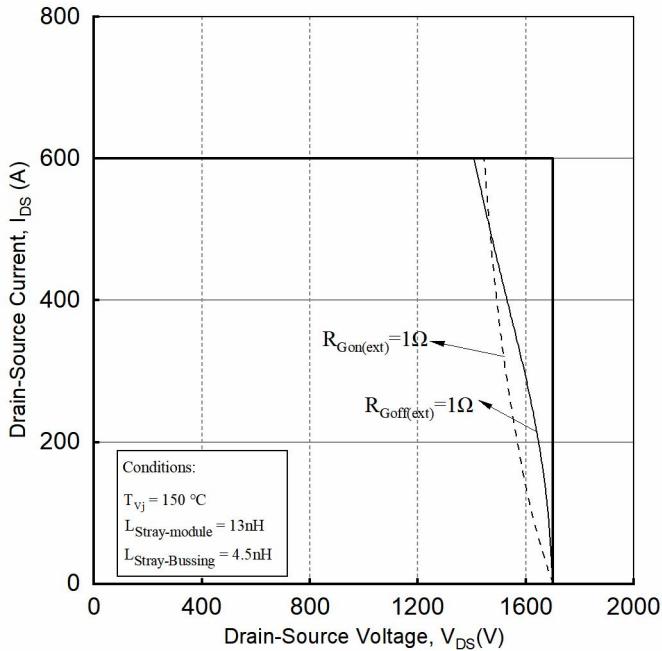


Figure 25. Reverse Bias Safe Operating Area (RBSOA)

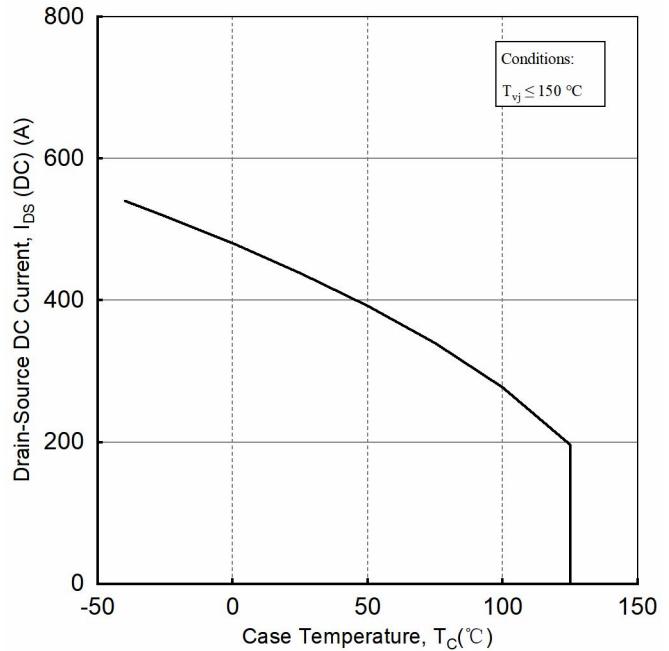


Figure 26. Continuous Drain Current Derating vs. Case Temperature

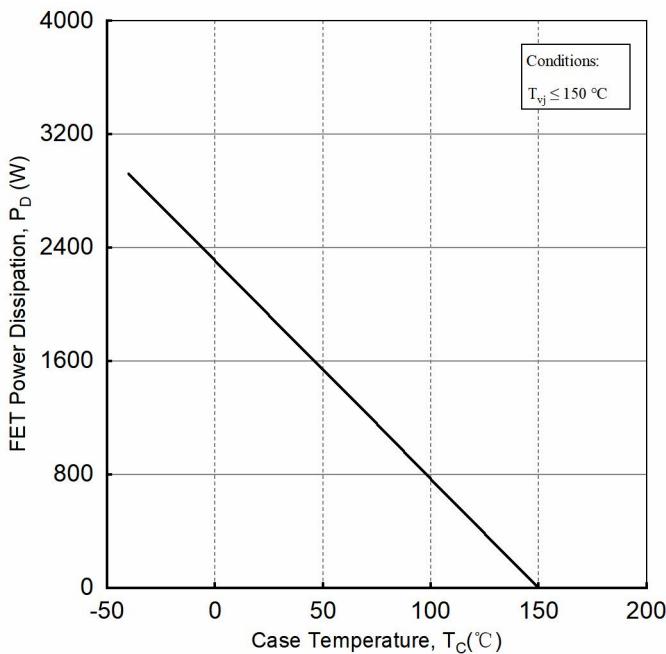


Figure 27. Maximum Power Dissipation Derating vs. Case Temperature

Definitions

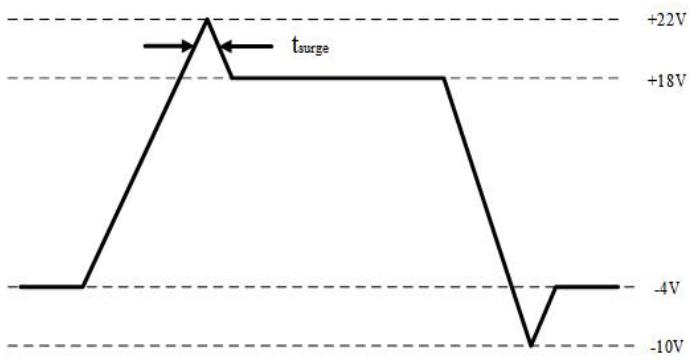


Figure 28. Example of acceptable V_{GS} waveform

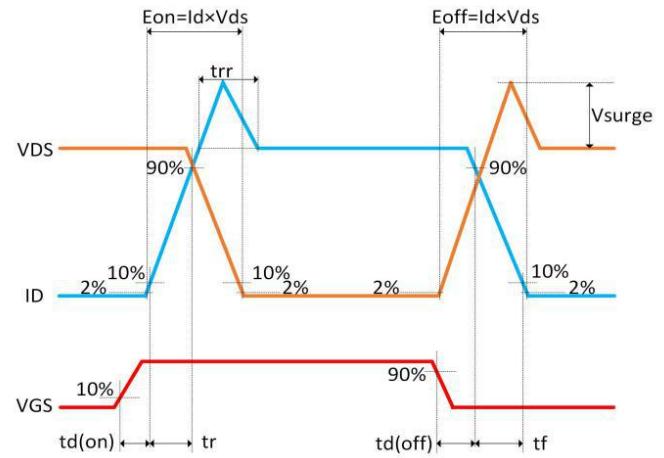


Figure 29. Wavelength for Switching Test

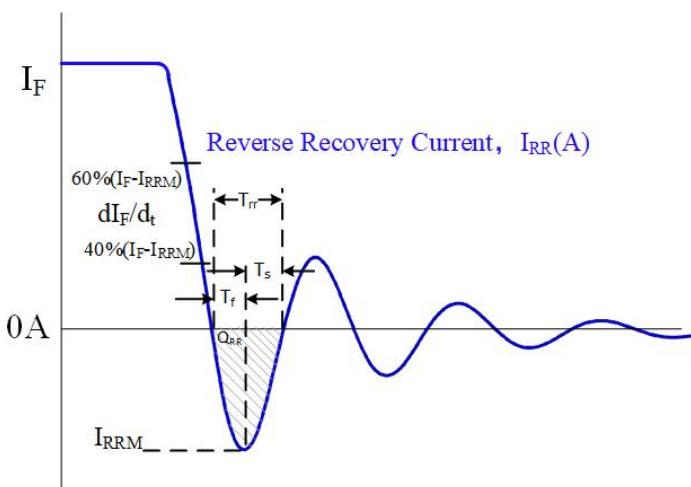
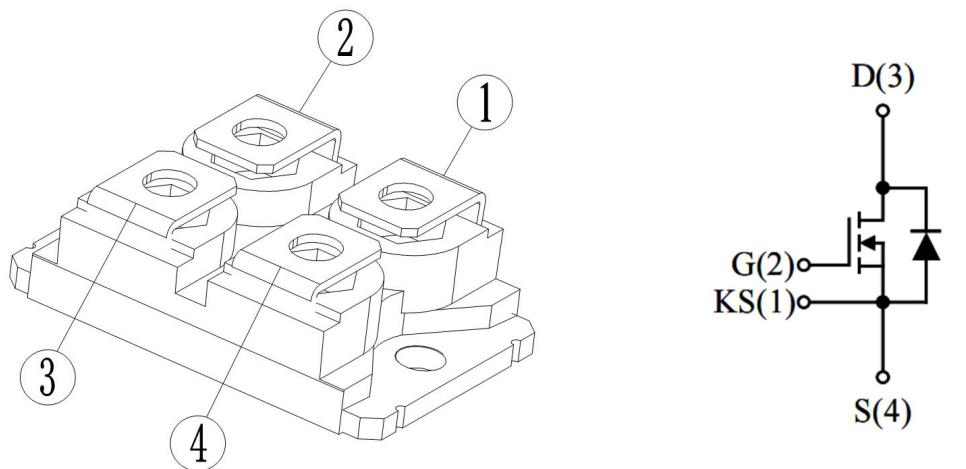


Figure 30. Reverse Recovery Definitions

Schematic



Package Dimensions

(The dimension unit is millimeter)

